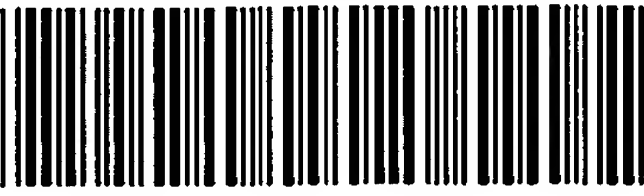


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
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370	230	7/5/2007	AK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Image and keyword search in USPTO, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached seach strategy)	7/5/2007	AK
Inventor name and Assignee search in PALM ExPo and EAST	7/5/2007	AK
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